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	Filing Date		2004-02-11	
	First Named Inventor	Takahiro Yamaguchi		
	Art Unit	2611		
	Examiner Name	E. Bayard		
Attorney Docket Number		02008/092002		

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1	Bendat, Julius S., Piersol, Allan G.; RANDOM DATA ANALYSIS MEASUREMENT PROCEDURES, Second Edition (Revised and Expanded); pp. 99-102	<input type="checkbox"/>
2	Dr. Feher, Kamilo; TELECOMMUNICATIONS MEASUREMENTS, ANALYSIS, AND INSTRUMENTATION; Professor, Electrical and Computer Engineering, University of California; Davis, California 95616; pp. 172-175	<input type="checkbox"/>
3	Co, Ramon S., Mulligan, J. H.; OPTIMIZATION OF PHASE-LOCKED LOOP PERFORMANCE IN DATA RECOVERY SYSTEMS, IEEE Journal of Solid-State Circuits, Vol. 29, No. 9, September 1994; pp. 1022-1054	<input type="checkbox"/>
4	Hajimiri, Ali, Limotyrakis, Sotirios, and Lee, Thomas H.; JITTER AND PHASE NOISE IN RING OSCILLATORS; IEEE Journal of Solid-State Circuits, Vol 34, No. 6, June 1999; pp. 790-804	<input type="checkbox"/>

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